,	Se	earch Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/516,333	AKIYAMA ET AL.	
Examiner	Art Unit	
Evan Pert	2826	

	SEAR	CHED	
Class	Subclass	Date	Examiner
29	25.35	11/12/2006	EΡ
310	311, 313A	11/12/2006	EP

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
29	25.35	11/12/2006	EP
310	311, 313A	11/12/2006	EP

SEARCH N (INCLUDING SEARC		·)
	DATE	EXMR
WEST BRS (printout of strategy in record)	11/12/2006	EP